

## 20V N-Channel Enhancement-Mode MOSFET

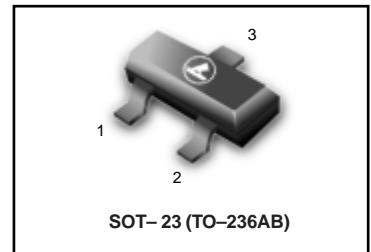
### ● APPLICATIONS

1) High Density Cell Design For Ultra Low On-Resistance

Improved Shoot-Through FOM

2) We declare that the material of product compliant with RoHS requirements and Halogen Free

### **LN2302LT1G**

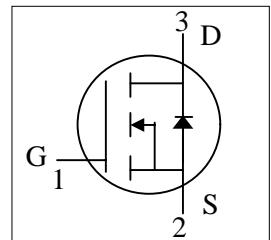


### ● FEATURES

V<sub>DS</sub>= 20V

R<sub>DS(ON)</sub>, V<sub>GS</sub>@4.5V, I<sub>DS</sub>@2.8A = 60mΩ

R<sub>DS(ON)</sub>, V<sub>GS</sub>@2.5V, I<sub>DS</sub>@2.0A = 115mΩ



### ● DEVICE MARKING AND ORDERING INFORMATION

Device	Marking	Shipping
LN2302LT1G	N02	3000/Tape&Reel
LN2302LT3G	N02	10000/Tape&Reel

### ● MAXIMUM RATINGS(Ta = 25°C)

Parameter	Symbol	Limits	Unit
Drain-to-Source Voltage	V <sub>DSS</sub>	20	V
Gate-to-Source Voltage	V <sub>GS</sub>	±8	V
Continuous Drain Current	I <sub>D</sub>	2.3	A
Pulsed Drain Current (Note1)	I <sub>DM</sub>	8	A
Maximum Power Dissipation	P <sub>D</sub>	0.9 0.57	W
T <sub>A</sub> = 25°C T <sub>A</sub> = 75°C			
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
Junction to Ambient Thermal Resistance(PCB mounted)(Note 2)	R <sub>θJA</sub>	145	°C/W

1. Repetitive Rating: Pulse width limited by the Maximum junction temperature

2. 1-in2 2oz Cu PCB board

# **LN2302LT1G**

## ● ELECTRICAL CHARACTERISTICS ( $T_a = 25^\circ C$ )

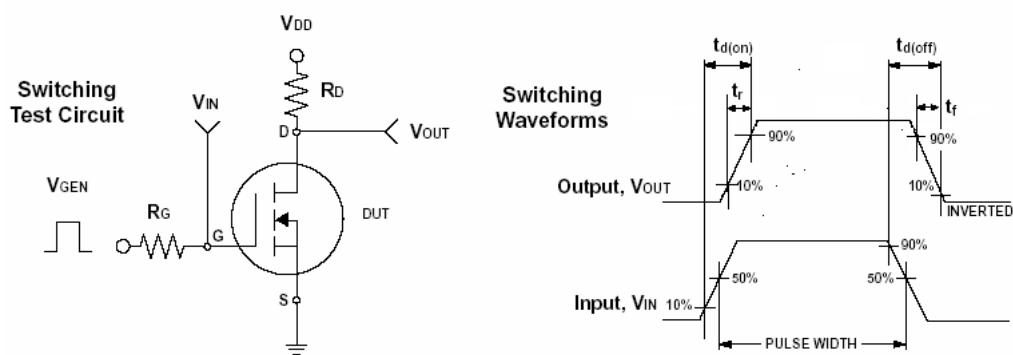
### STATIC

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Drain-to-Source Breakdown Voltage	$V(BR)_{DSS}$	20	—	—	V	$V_{GS} = 0 V, I_D = 250 \mu A$
Gate Threshold Voltage	$V_{GS(TH)}$	0.6	0.95	1.2	V	$V_{GS} = V_{DS}, I_D = 250 \mu A$
Zero Gate Voltage Drain Current	$I_{DSS}$	—	—	-1	$\mu A$	$V_{DS}=9.6V, V_{GS}=0V$
Gate-to-Source Leakage Current	$I_{GSS}$	—	—	$\pm 100$	nA	$V_{DS} = 0 V, V_{GS} = \pm 8 V$
		—	40	60	$m\Omega$	$V_{GS} = 4.5 V, I_D = 2.8 A$
Drain-to-Source On Resistance	$R_{DS(on)}$	—	50	115	$m\Omega$	$V_{GS} = 2.5 V, I_D = 2 A$
Forward Diode Voltage	$V_{SD}$			1.2	V	$V_{GS} = 0 V, I_{SD} = -1.6 A$
Forward Transconductance	$g_{FS}$	—	6.5	—	S	$V_{DS} = 5.0 V, I_D = 4 A$

### DYNAMIC (Note 3)

Input Capacitance	$C_{iss}$	—	427.12	—	pF	$V_{GS} = 0 V, f = 1.0 \text{ MHz}, V_{DS} = 6 V$
Output Capacitance	$C_{oss}$	—	80.56	—		
Reverse Transfer Capacitance	$C_{rss}$	—	57.00	—		
Total Gate Charge	$Q_G$	—	3.69	—	nC	$V_{GS} = 4.5 V, V_{DS} = 6 V$ $I_D = 2.8 A$
Gate-to-Source Gate Charge	$Q_{GS}$	—	0.70	—		
Gate-to-Drain Charge	$Q_{GD}$	—	1.06	—		
Turn-On Delay Time	$t_{d(on)}$	—	6.16	—	ns	$V_{DD} = 6V, R_L = 6 \Omega$ $I_D = 1A, V_{GEN} = 4.5V$ $R_G = 6 \Omega$
Rise Time	$t_r$	—	7.56	—		
Turn-Off Delay Time	$t_{d(off)}$	—	16.61	—		
Fall Time	$t_f$	—	4.07	—		

3. Pulse test: pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$



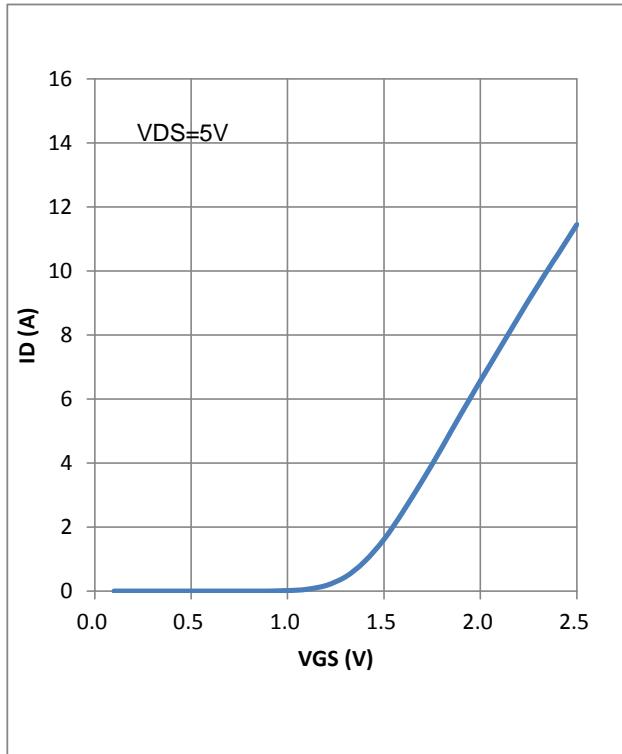
**LN2302LT1G**
**ELECTRICAL CHARACTERISTIC CURVES**


FIG.1 Transfer Characteristics

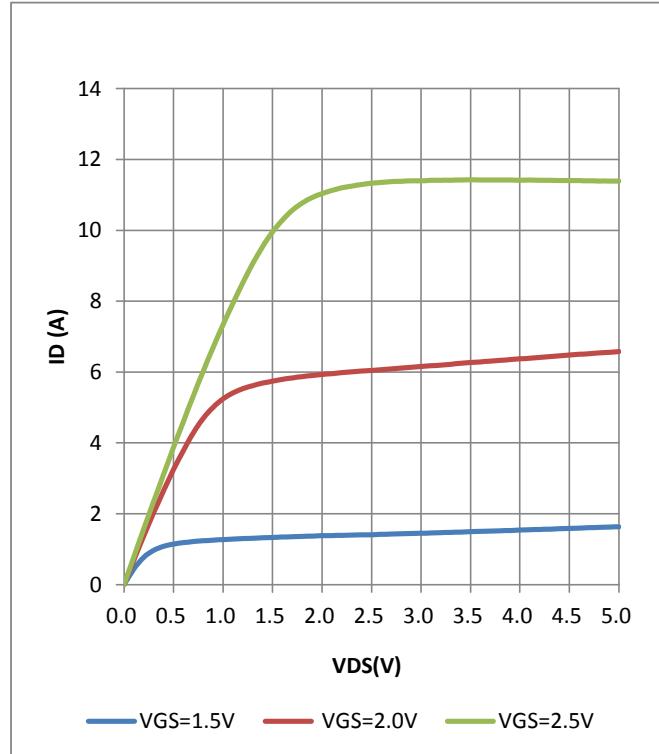


FIG.2 On-Region Characteristics

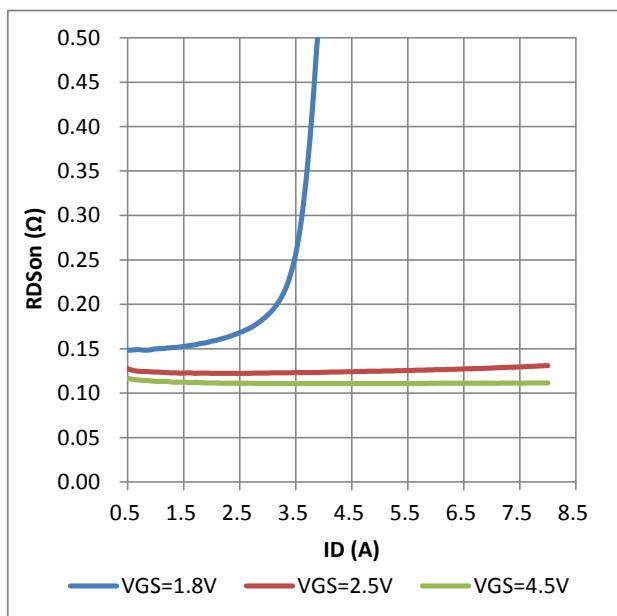


FIG.3 On-Resistance vs. Drain Current

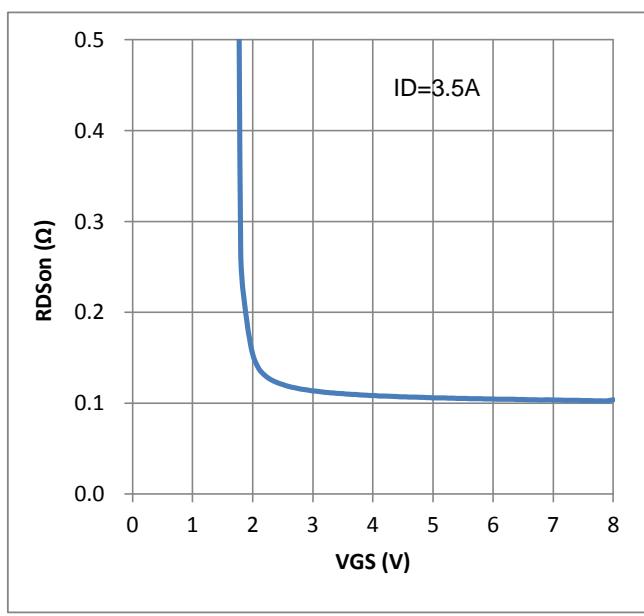


FIG.4 On-Resistance vs. Gate-to-Source Voltage

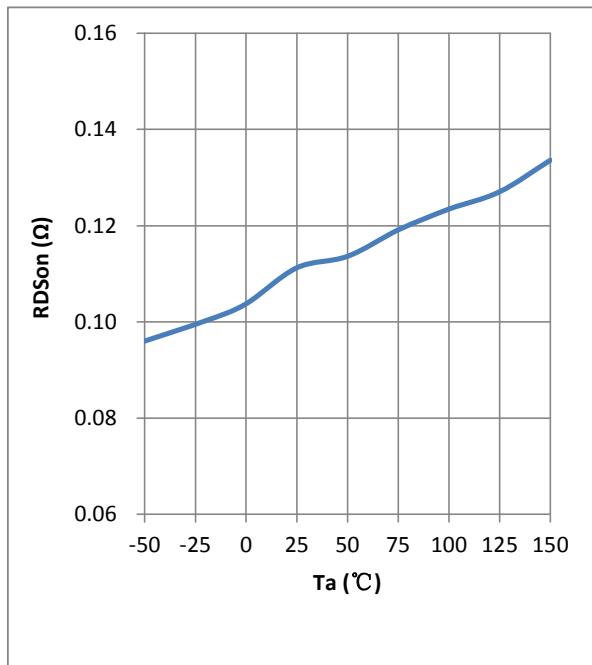
**LN2302LT1G****ELECTRICAL CHARACTERISTIC CURVES**

FIG.7 On-Resistance vs. Junction Temperature

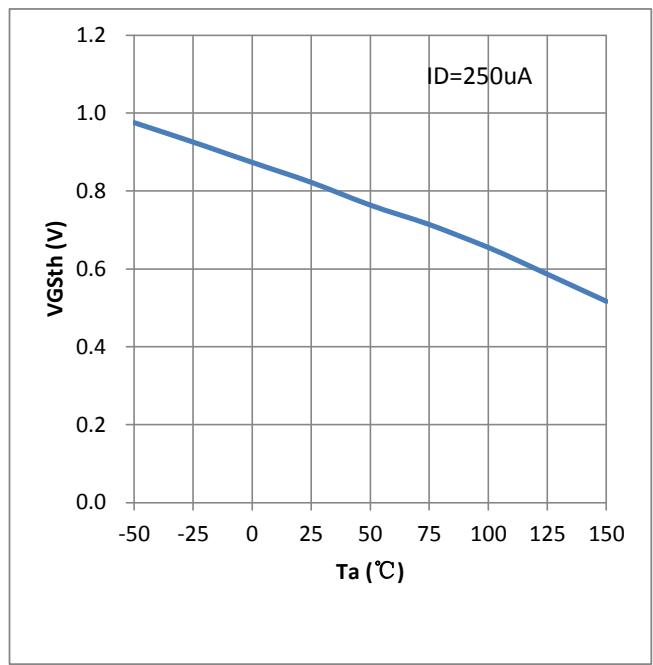
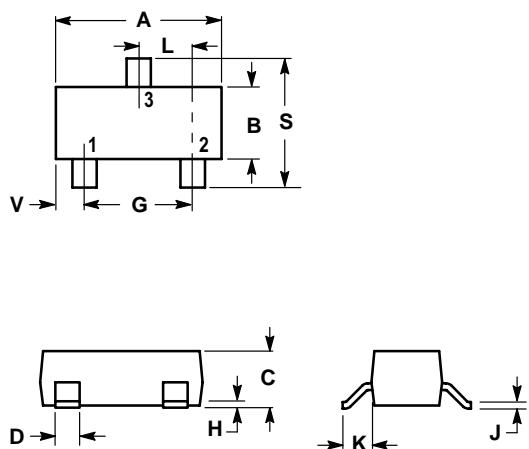


FIG.8 VTH vs. Junction Temperature

# **LN2302LT1G**

## **SOT-23**



### NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982
2. CONTROLLING DIMENSION: INCH.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.1102	0.1197	2.80	3.04
B	0.0472	0.0551	1.20	1.40
C	0.0350	0.0440	0.89	1.11
D	0.0150	0.0200	0.37	0.50
G	0.0701	0.0807	1.78	2.04
H	0.0005	0.0040	0.013	0.100
J	0.0034	0.0070	0.085	0.177
K	0.0140	0.0285	0.35	0.69
L	0.0350	0.0401	0.89	1.02
S	0.0830	0.1039	2.10	2.64
V	0.0177	0.0236	0.45	0.60

